

ON Semiconductor®

ISL9V2540S3ST EcoSPARK® N-Channel Ignition IGBT 250mJ, 400V

Features

- SCIS Energy = 250mJ at T_J = 25°C
- Logic Level Gate Drive
- Qualified to AEC Q101
- RoHS Compliant

Applications

- Automotive Ignition Coil Driver Circuits
- Coil On Plug Applications

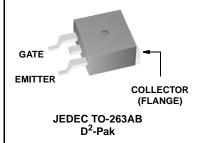


General Description

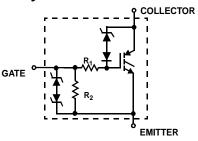
The ISL9V2540S3ST is a next generation ignition IGBT that offers outstanding SCIS capability in the industry standard D²-Pak (TO-263) plastic package. This device is intended for use in automotive ignition circuits, specifically as a coil driver. Internal diodes provide voltage clamping without the need for external components.

EcoSPARK® devices can be custom made to specific clamp voltages. Contact your nearest ON Semiconductor sales office for more information.

Package



Symbol



Device Maximum Ratings	$T_A = 25^{\circ}C$ unless otherwise noted
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Symbol	Parameter	Ratings	Units
BV _{CFR}	Collector to Emitter Breakdown Voltage (I _C = 1 mA)	430	V
BV _{FCS}	Emitter to Collector Voltage - Reverse Battery Condition (I _C = 10 mA)	24	V
E _{SCIS25}	At Starting T _{.I} = 25°C, I _{SCIS} = 12.9A, L = 3.0mHy	250	mJ
E _{SCIS150}	At Starting $T_L = 150$ °C, $I_{SCIS} = 10A$, $L = 3.0$ mHy	150	mJ
I _{C25}	Collector Current Continuous, At T _C = 25°C, See Fig 9	15.5	Α
I _{C110}	Collector Current Continuous, At T _C = 110°C, See Fig 9	15.3	Α
V_{GEM}	Gate to Emitter Voltage Continuous	±10	V
P _D	Power Dissipation Total T _C = 25°C	166.7	W
	Power Dissipation Derating T _C > 25°C	1.11	W/°C
T	Operating Junction Temperature Range	-40 to 175	°C
T _{STG}	Storage Junction Temperature Range	-40 to 175	°C
T _I	Max Lead Temp for Soldering (Leads at 1.6mm from Case for 10s)	300	°C
T _{pka}	Max Lead Temp for Soldering (Package Body for 10s)	260	°C
ESD	Electrostatic Discharge Voltage at 100pF, 1500Ω (HBM)	4	kV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
V2540S	ISL9V2540S3ST	TO-263AB	330mm	24mm	800 units

Electrical Characteristics T_A = 25°C unless otherwise noted

Collector to Emitter Saturation Voltage

 $V_{CE(SAT)}$

Symbol	Parameter	Test Conditions		Min	Typ	Max	Units
ff State	Characteristics						
BV _{CER}	Collector to Emitter Breakdown Voltage	$I_C = 2mA$, $V_{GE} = 0$, $R_G = 1K\Omega$, See Fig. 15 $T_{\perp} = -40$ to 150°C		370	400	430	V
BV _{CES}	Collector to Emitter Breakdown Voltage	$I_C = 10$ mA, $V_{GE} = 0$, $R_G = 0$, See Fig. 15 $T_{.1} = -40$ to 150°C		390	420	450	V
BV _{ECS}	Emitter to Collector Breakdown Voltage	$I_C = -75 \text{mA}, V_{GE} = 0 \text{V},$ $T_C = 25 ^{\circ}\text{C}$		30	-	-	V
BV_{GFS}	Gate to Emitter Breakdown Voltage	$I_{GES} = \pm 2mA$		±12	±14	-	V
I _{CER}	Collector to Emitter Leakage Current	V_{CER} = 250V, R_G = 1KΩ, See Fig. 11	$T_C = 25^{\circ}C$	-	-	25	μΑ
			T _C = 150°C	-	-	1	mA
200	Emitter to Collector Leakage Current	$V_{EC} = 24V$, See	$T_C = 25^{\circ}C$	-	-	1	mA
	$T_{\rm C} = 150^{\circ}{\rm C}$	-	-	40	mA		
R_1	Series Gate Resistance	-		-	70	-	Ω
R_2	Gate to Emitter Resistance			10K	1	26K	Ω
n State	Characteristics						
V _{CE(SAT)}	Collector to Emitter Saturation Voltage	$I_C = 6A$, $V_{GF} = 4V$	T _C = 25°C, See Fig. 3	-	1.37	1.8	V

 $V_{GF} = 4V$ I_C = 10A, V_{GF} = 4.5V

T_C = 150°C

See Fig. 4

1.77

2.2

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$Q_{G(ON)}$	Gate Charge	$I_C = 10A$, $V_{CE} = 12V$, $V_{GE} = 5V$, See Fig. 14		-	15.1	-	nC
V _{GE(TH)}	Gate to Emitter Threshold Voltage	$I_C = 1.0 \text{mA}, T_C =$		1.3	-	2.2	V
OE(III)		$V_{CE} = V_{GE}$, $T_{C} =$ See Fig. 10		0.75	-	1.8	V
V_{GEP}	Gate to Emitter Plateau Voltage	$I_C = 10A,$ $V_{CE} = 12V$		-	3.1	-	V
	Characteristics	V 44V D 40	T				
t _{d(ON)R} t _{riseR}	Current Turn-On Delay Time-Resistive Current Rise Time-Resistive	$V_{CE} = 14V, R_L = 1Ω,$ $V_{GE} = 5V, R_G = 1KΩ$ $T_{.J} = 25^{\circ}C$ $V_{CE} = 300V, L = 500μHy,$ $V_{GE} = 5V, R_G = 1KΩ$ $T_{.J} = 25^{\circ}C, See Fig. 12$		-	2.17	-	μs μs
t _{d(OFF)}	Current Turn-Off Delay Time-Inductive			-	3.64	-	μs
t _{fL}	Current Fall Time-Inductive			-	2.36	-	μs
SCIS	Self Clamped Inductive Switching	$T_J = 25^{\circ}\text{C}, L = 3.0\text{mH}$ $R_G = 1\text{K}\Omega, V_{GE} = 5\text{V}$ Fig. 1 & 2	-	=	-	250	mJ

Typical Performance Curves

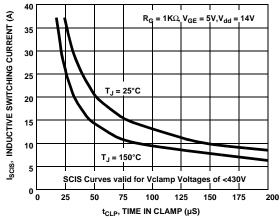


Figure 1. Self Clamped Inductive Switching Current vs Time in Clamp

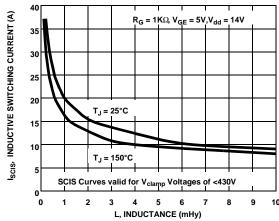


Figure 2. Self Clamped Inductive Switching Current vs Inductance

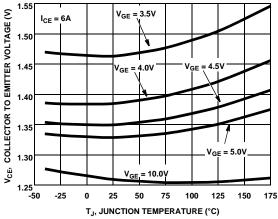


Figure 3. Collector to Emitter On-State Voltage vs Junction Temperature

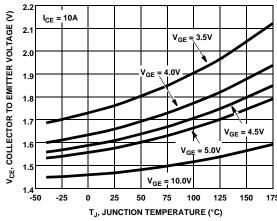


Figure 4. Collector to Emitter On-State Voltage vs Junction Temperature

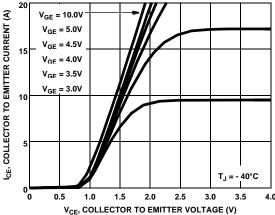


Figure 5. Collector to Emitter On-State Voltage vs Collector Current

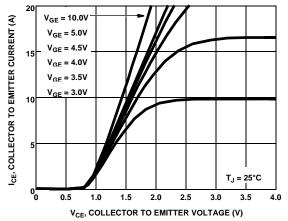


Figure 6. Collector to Emitter On-State Voltage vs Collector Current

Typical Performance Curves (Continued) _{(CE}, COLLECTOR TO EMITTER CURRENT (A) COLLECTOR TO EMITTER CURRENT (A) V_{GE} = 10.0V DUTY CYCLE < 0.5%, V_{CE} = 5V PULSE DURATION = 250 μ s $V_{GE} = 5.0V$ 15 $V_{\rm GE} = 4.5 V$ 15 $V_{GE} = 4.0V$ $T_J = 175$ °C $V_{GE} = 3.5V$ 10 10 $V_{GE} = 3.0V$ <u>ű</u> T_J = -40°C $T_J = 175^{\circ}C$ 0 1.0 0.5 3.5 1.5 4.0 2.0 2.5 3.0 3.5 V_{CE}, COLLECTOR TO EMITTER VOLTAGE (V) V_{GE}, GATE TO EMITTER VOLTAGE (V) Figure 7. Collector to Emitter On-State Voltage vs Figure 8. Transfer Characteristics **Collector Current** 2.0 V_{CE} = V_{GE} V_{GE} = 4.0V I_{CE} = 1mA V_{TH}, THRESHOLD VOLTAGE (V) I_{CE}, DC COLLECTOR CURRENT (A) 12 10 1.4 0 25 1.0 -50 125 150 100 125 50 75 100 150 T_C, CASE TEMPERATURE (°C) T_J JUNCTION TEMPERATURE (°C) Figure 9. DC Collector Current vs Case Figure 10. Threshold Voltage vs Junction **Temperature Temperature** 10000 Inductive toFF $I_{CE} = 6.5A$, $V_{GE} = 5V$, $R_{G} = 1K\Omega$ <u>F</u> SWITCHING TIME (µS) LEAKAGE CURRENT 100 Resistive t_{OFF} 10 Resistive toN /_{CES} = 250V 100 50 75 100 T_J , JUNCTION TEMPERATURE (°C) T_J, JUNCTION TEMPERATURE (°C) Figure 11. Leakage Current vs Junction Figure 12. Switching Time vs Junction Temperature **Temperature**

Typical Performance Curves (Continued) 1500 FREQUENCY = 1 MHz 1250 C, CAPACITANCE (pF) 1000 CIES 500 CRES 250 COES 10 15 20 VCE, COLLECTOR TO EMITTER VOLTAGE (V) Figure 13. Capacitance vs Collector to Emitter Voltage 445

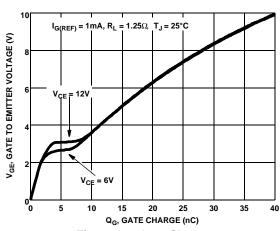


Figure 14. Gate Charge

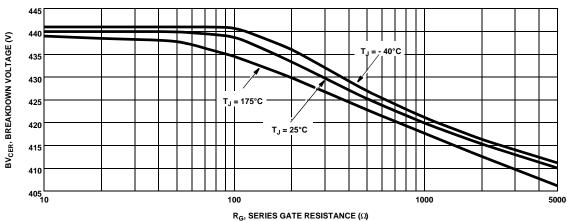


Figure 15. Breakdown Voltage vs Series Gate Resistance

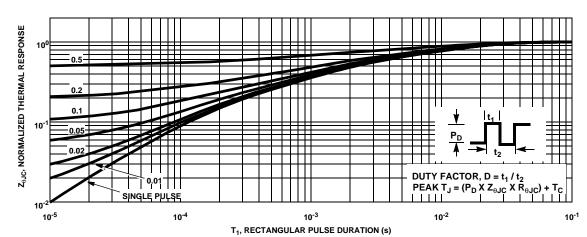


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

Test Circuit and Waveforms

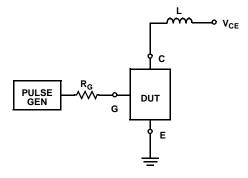


Figure 17. Inductive Switching Test Circuit

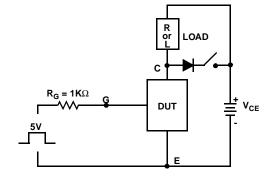


Figure 18. t_{ON} and t_{OFF} Switching Test Circuit

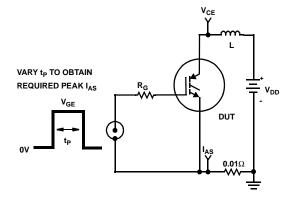


Figure 19. Unclamped Energy Test Circuit

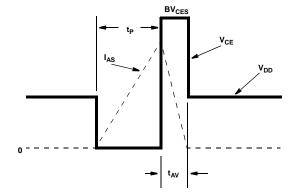


Figure 20. Unclamped Energy Waveforms

SPICE Thermal Model JUNCTION REV 16 May 2005 ISL9V2540S3ST CTHERM1 th 6 19e -4 CTHERM2 6 5 12e -3 RTHERM1 CTHERM1 CTHERM3 5 4 15e -3 CTHERM4 4 3 25e -3 6 CTHERM5 3 2 69e -3 CTHERM6 2 tl 100e -3 RTHERM2 CTHERM2 RTHERM1 th 6 80e -3 5 RTHERM2 6 5 81e -3 RTHERM3 5 4 82e -3 RTHERM4 4 3 100e -3 CTHERM3 RTHERM3 RTHERM5 3 2 150e -3 RTHERM6 2 tl 1645e -4 4 SABER Thermal Model RTHERM4 CTHERM4 ISL9V2540S3ST template thermal_model th tl thermal_c th, tl 3 ctherm.ctherm1 th 6 = 19e -4 RTHERM5 CTHERM5 ctherm.ctherm2 65 = 12e - 3ctherm.ctherm3 5 4 = 15e -3 2 ctherm.ctherm4 4 3 = 25e - 3ctherm.ctherm5 3 2 = 69e -3 CTHERM6 RTHERM6 ctherm.ctherm6 2 tl = 100e -3 rtherm.rtherm1 th 6 = 80e -3 rtherm.rtherm2 6 5 = 81e -3 rtherm.rtherm3 5 4 = 82e -3 CASE rtherm.rtherm4 4 3 = 100e -3 rtherm.rtherm5 3 2 = 150e -3 rtherm.rtherm6 2 tl = 1645e -4

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